# Perpendicular Magnetic Anisotropy Features of [Co/Pd] Multilayer Matrix and Related Synthetic Anti-Ferromagnet Structure 

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## 1. Introduction

Perpendicular spin torque transfer magnetic random access memories ( $p$-STT MRAMs) are increasingly becoming one of the most reliable candidates for use in practical devices. ${ }^{1}$ In past years, among various PMA materials including a $L 1_{0}$ alloy, multilayer (ML), and rare earth-transition metal (RE-TM) alloy, the artificial ML matrix consists of ferromagnetic metals and noble metals, such as $\mathrm{Co} / \mathrm{Pd}, \mathrm{Co} / \mathrm{Pt}, \mathrm{Fe} / \mathrm{Pd}$, and $\mathrm{Fe} / \mathrm{Pt},{ }^{2-4}$ and their alloy compositions ${ }^{5-7}$ have been widely explored due to its large PMA features.

## 2. Experimental Details

Various $[\mathrm{Co} / \mathrm{Pd}]$ MLs with $\mathrm{Ta} / \mathrm{Ru} / \mathrm{Pd}$ seed layers were prepared by utilizing a DC/RF-magnetron sputtering system on oxidized Si substrates at room temperature. After the different thicknesses of the Co and Pd layers were tested within a nominal thickness range from $1 \AA$ to $9 \AA$, the optimized thicknesses were selected for subsequent evaluation in this work. Two samples were prepared as follows: subs. $/ \mathrm{Ta} / \mathrm{Ru} / \mathrm{Pd} /[\mathrm{Co} / \mathrm{Pd}]_{7} / \mathrm{Pd}$ (Sample A) and subs. $/ \mathrm{Ta} / \mathrm{Ru} / \mathrm{Pd} /[\mathrm{CoO} / \mathrm{Pd}]_{2} /[\mathrm{Co} / \mathrm{Pd}]_{7} / \mathrm{Pd}$ (Sample B). The CoOlayer was grown by a reactive sputtering method, while the other Co layer was fabricated under only an Ar ambient. Finally, post thermal annealing was carried out at various temperatures under perpendicular magnetic field of 3 Tesla.

## 3. Results and Discussion

The ordinary ML matrix (Sample A) revealed an anisotropic energy of around $3 \mathrm{Merg} / \mathrm{cc}$, while the modified [Co/Pd] ML matrix (Sample B) provided a significantly higher $K_{U}$ value of $7.43 \mathrm{Merg} / \mathrm{cc}$ after annealing. By utilizing the high-resolution x-ray diffraction (HR-XRD) $\theta-2 \theta$ scan, all the samples have been confirmed to have a (111) crystal orientation. The Rocking curve measurement showed that the crystal orientation quality of annealed Sample B seems to be better than that of Sample A. Therefore, we expect that the difference in the main peak location, peak shift, and FWHM widths between Sample A and B may be associated with the induced lattice strain in the Sample B under annealing.The x-ray photoelectron spectroscopy (XPS) suggests an evidence for the presence of Co-O bonding states and annealing dependent oxygen atom diffusion event, along with HR-XRD results.

## 4. Conclusion

In summary, we present thermally stable behaviors of $[\mathrm{Co} / \mathrm{Pd}]_{\mathrm{n}}$ ML matrix incorporated with a $[\mathrm{CoO} / \mathrm{Pd}]_{\mathrm{m}}$ bottom layer. Post thermal annealing even at the higher temperature of $450^{\circ} \mathrm{C}$ allows for a proper diffusion process of oxygen atoms associated with initially formed Co-O binding during deposition. The diffused oxygen atoms may lead to structural reconfiguration in the ML matrix by providing proper lattice strains in the $[\mathrm{Co} / \mathrm{Pd}] \mathrm{ML}$ framework. The ordinary ML matrix revealed an effective anisotropic energy of around $1.25 \mathrm{Merg} / \mathrm{cc}$, while the modified [Co/Pd] ML matrix provided a significantly higher $K_{\text {eff }}$ value of $3.40 \mathrm{Merg} / \mathrm{cc}$ after annealing.

## 5. References

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